

Search Notes

Application/Control No.

10/667,249

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under
Reexamination

LEFFEL, MICHAEL DAVID

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	149.ccls. and table and (pre near1 distort\$3)	06/01/06	NKV
375	296.ccls. and table and (pre near1 distort\$3)	06/01/06	NKV
375	297.ccls. and table and (pre near1 distort\$3)	06/01/06	NKV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR